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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/039,459	11/07/2001	Hariprasad Sreedharamurthy	MEMC 99-1250/2441.1	1061
321 7	590 05/21/2003			
SENNIGER POWERS LEAVITT AND ROEDEL			EXAMINER	
ONE METROPOLITAN SQUARE 16TH FLOOR			SONG, MATTHEW J	
ST LOUIS, MO) 63102		ART UNIT	PAPER NUMBER
			1765	ſ
			DATE MATERIA OSCILIZADA	·

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)				
	10/039,459	SREEDHARAMURTHY ET AL.				
Office Action Summary	Examin r	Art Unit				
	Matthew J Song	1765				
Th MAILING DATE of this communication app Period for Reply	ears on the cover she it with the c	orrespond nc address				
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status	66(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days fill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	ely filed will be considered timely. the mailing date of this communication. (35 U.S.C. § 133).				
1) Responsive to communication(s) filed on 21 h	<u> 1arch 2003</u> .					
2a) This action is FINAL . 2b) ⊠ Thi	is action is non-final.					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims						
4)⊠ Claim(s) 1-33 is/are pending in the application.						
4a) Of the above claim(s) <u>15-33</u> is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1-14</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/or election requirement.						
Application Papers						
9) The specification is objected to by the Examiner.						
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.						
If approved, corrected drawings are required in reply to this Office action.						
12) The oath or declaration is objected to by the Examiner.						
Priority under 35 U.S.C. §§ 119 and 120						
13) Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. § 119(a)-(d) or (f).				
a) ☐ All b) ☐ Some * c) ☐ None of:						
1. Certified copies of the priority documents	s have been received.					
2. Certified copies of the priority documents		on No				
Copies of the certified copies of the prior application from the International But See the attached detailed Office action for a list.	rity documents have been receive reau (PCT Rule 17.2(a)).	ed in this National Stage				
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).						
a) ☐ The translation of the foreign language pro 15)☐ Acknowledgment is made of a claim for domesti						
Attachment(s)						

U.S. Patent and Trademark Office PTO-326 (Rev. 04-01)

Notice of References Cited (PTO-892)
 Notice of Draftsperson's Patent Drawing Review (PTO-948)

3) Information Disclosure Statement(s) (PTO-1449) Paper No(s)

6) Other:

4) Interview Summary (PTO-413) Paper No(s). ____ 5) Notice of Informal Patent Application (PTO-152)

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DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Holder et al (WO 99/66108).

Holder et al discloses an Czochralski apparatus for preparing silicon crystals with reduced metal content, note entire reference, comprising graphite hot zone structures: a heater 16, susceptor 14, thermal shield 18, heat reflectors, pure tubes, insulation and view port channels and a crystal growth chamber 4. Holder et al also discloses the graphite utilized to construct the hot zone structures is generally at least 99.99% pure graphite with less than about 5 ppm, where the particle generation during high temperature heating decreases as the purity of the graphite increases (pg 7), this is a teaching that purity is a result effective variable. Holder et al also discloses a protective coating of silicon carbide about 75-150 micrometers thick covering the entire surface to grown directly on the graphite components covering the entire surface to maximize protection comprises 99.99% silicon carbide and 0.01% silicon. Holder et al also teaches the silicon carbide coating provided by industry contains about 1 ppm iron (pg 3).

Holder et al discloses a graphite substrate with a concentration of iron no greater than 5 ppm and a silicon carbide coating, thereon. Holder et al does not disclose a substrate with a concentration of iron no greater than 1.5x 10¹² atoms/cm³ or an iron concentration of the

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protective layer is no greater than 1.0×10^{12} atoms/cm³. It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify Holder et al by using a substrate with a reduced iron impurity concentration because purifying an old product is held to be obvious (MPEP 2144.04 VII). Also note, the mere purity of a product, by itself does not render the product unobvious (Ex parte Gray, 10 USPO2d 1922 (Bd. Pat. App. & Inter. 1989).

Referring to claim 7-8, Holder et al discloses a layer thickness of 75-125 micrometers.

Referring to claim 9, Holder et al discloses covering the entire surface to maximize the effectiveness.

3. Claims 10 and 14 are rejected under 35 U.S.C. 103(a) as being unpatentable over Holder et al (WO 99/66108) in view of Falster et al (US 5,919,302) and Kim et al (US 5,942,032).

Holder et al discloses all of the limitations of claim 10, as discussed previously, except the structure component reaches at least 950°C for at least about 80 hours and is within 3 cm to about 5 cm of the silicon single crystal or the silicon melt.

In a Czochralski method for forming low defect density silicon, note entire reference,

Falster et al teaches a ingot is cooled from a solidification temperature to a temperature in excess
of about 1050°C over a period of at least about 75 hours and control of the cooling rate can be
achieved by using any means currently known in the art for minimizing heat transfer, including
the use of insulators, heaters, radiation shields and magnetic fields (col 9, ln 1-67). It would have
been obvious to a person of ordinary skill in the art at the time of the invention to modify Holder
et al with Falster et al to form an ingot having an axially symmetric region, which is substantially
free of defects (col 3, ln 1-67).

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In a single crystal pulling apparatus, note entire reference, Kim et al discloses a lower heat shield 42 is about 50-60 mm above the surface of a the melt in a crucible (col 9, ln 1-67) to prevent heat from radiating from the side walls of the crucible to a ingot except in the space between the bottom of the lower heat shield and the surface of the melt. Kim et al also discloses an upper heat shield 36, an intermediate heat shield 40 and vertically arranged heating panels 24, where the heating panel which heats the interior of the crystal puller reads on applicant's upper heater, composed of graphite and the intermediate heat shield supports the upper heat shield (col 6, ln 1-67). It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify the combination of Holder et al and Falster et al with Kim et al to inhibit agglomeration of defects in the crystal growth process (col 3, ln 1-67).

4. Claims 11-13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Holder et al (WO 99/66108) in view of Falster et al (US 5,919,302) and Kim et al (US 5,942,032) as applied to claims 10 and 14 above, and further in view of Luter et al (5,922,127).

The combination of Holder et al, Falster et al and Kim et al teaches all of the limitations of claim 11, as discussed previously, except a lower heat shield reflector, a lower heat shield outer reflector, a lower heat shield insulation layer

In a crystal pulling apparatus, note entire reference, Luter et al discloses a heat shield 40 comprising a graphite insulation layer 42 sandwiched between an inner 42 and outer reflector 46. It would have been obvious to a person of ordinary skill in the art at the time of the invention to modify the combination of Holder et al, Falster et al and Kim et al with Luter et al to distribute

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defects more evenly throughout the ingot to improve the overall quality of the ingot (col 6, ln 50-67).

Referring to claim 11, the combination of Holder et al, Falster et al, Kim et al and Luter et al teaches inner 42 and outer reflector 46, a upper heat shield 36, an intermediate heat shield 40, lower heat shield 42, an upper heater 24, where the intermediate heat shield provides support for the upper heat shield, which acts as an insulation shield.

Referring to claim 12-13, the combination of Holder et al, Falster et al, Kim et al and Luter et al teaches a silicon carbide layer covering graphite components in a hot zone, including reflectors, insulation, heaters and heat shields.

Response to Arguments

5. Applicant's arguments with respect to claims 1-14 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

6. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Tojo et al (JP 11-116344) teaches a SiC product, which has impurity concentrations comprising a Fe concentration of less than 0.5 ppm (Abstract).

Nishimura et al (JP 02-192413) teaches a method of eliminating impurities in a graphite member (Abstract).

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Nadkarni et al (US 5,080,879) teaches a method of purfying silicon carbide of impurities,

such as iron, note entire reference.

Tanaka et al (US 4,753,763) teaches a method of purifying silicon carbide (Abstract).

7. Any inquiry concerning this communication or earlier communications from the examiner

should be directed to Matthew J Song whose telephone number is 703-305-4953. The examiner

can normally be reached on M-F 9:00-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Benjamin L Utech can be reached on 703-308-3868. The fax phone numbers for the

organization where this application or proceeding is assigned are 703-872-9310 for regular

communications and 703-872-9311 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is 703-308-0661.

Matthew J Song Examiner

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MJS

May 20, 2003

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BENJAMIN L. UTECH SUPERVISORY PATENT EXAMINER

TECHNOLOGY CENTER 1700